



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. 10/655,997
Filing Date September 5, 2003
Inventor Jon P. Daley
Assignee Micron Technology, Inc.
Group Art Unit 2822
Examiner Pamela E. Perkins
Attorney's Docket No. MI22-2380
Customer No. 021567
Title: Methods of Forming Patterned Photoresist Layers Over Semiconductor Substrates

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a Request for Continued Examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: 12-1-05

By: 
Mark S. Matkin
Reg. No. 32,268

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| | | | | FILING DATE September 5, 2003 | GROUP ART UNIT 2822 | | |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
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